

Understanding Computational Capabilities of COTS DRAM Chips

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OMEM-201-1: Emerging Memory Architectural Advancements

06/08/2025

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The Capability of COTS DRAM Chips

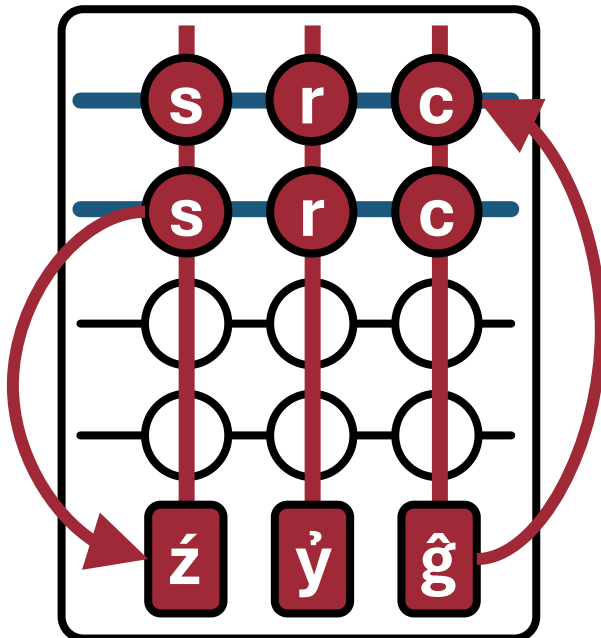
We demonstrate that COTS DRAM chips:

- 1 Can copy one row into up to 31 other rows with $>99.98\%$ success rate
- 2 Can perform **NOT operation** with up to **32 output operands**
- 3 Can perform up to **16-input AND, NAND, OR, and NOR** operations

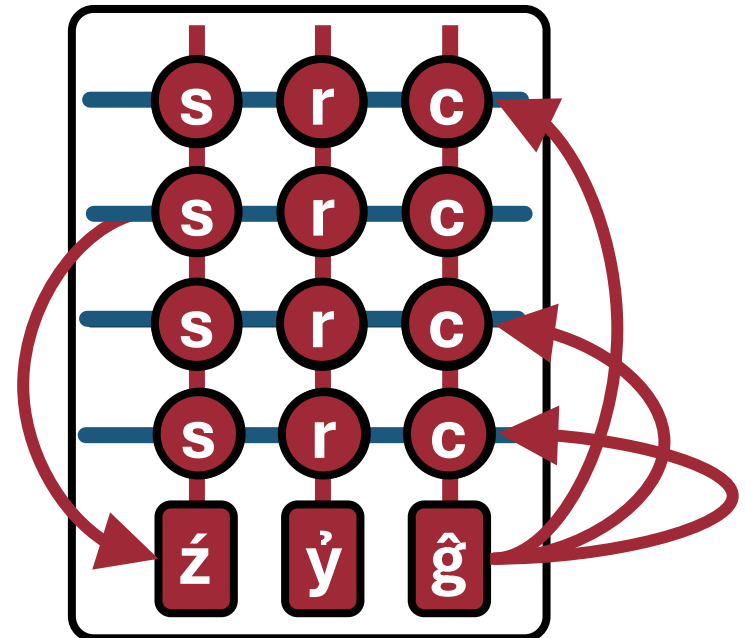
In-DRAM Multiple Row Copy (Multi-RowCopy)

Simultaneously activate many rows to copy **one row's content** to **multiple destination rows**

RowClone

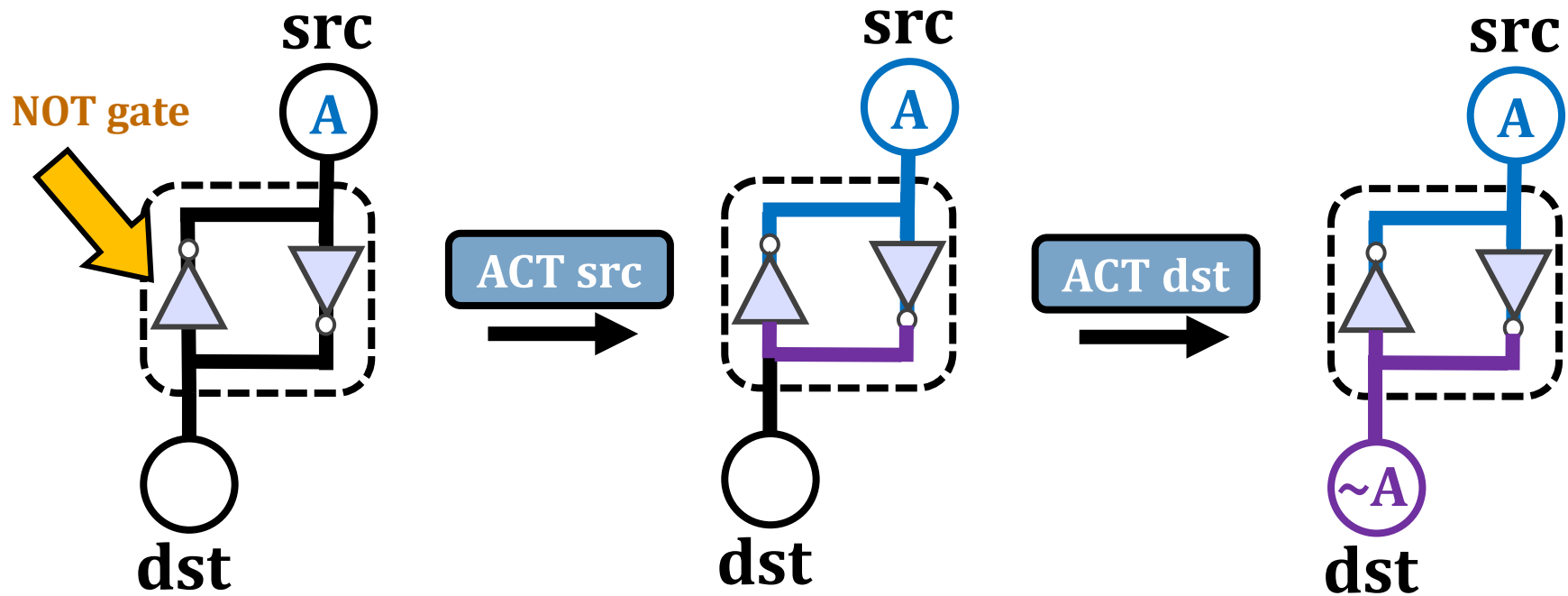


Multi-RowCopy



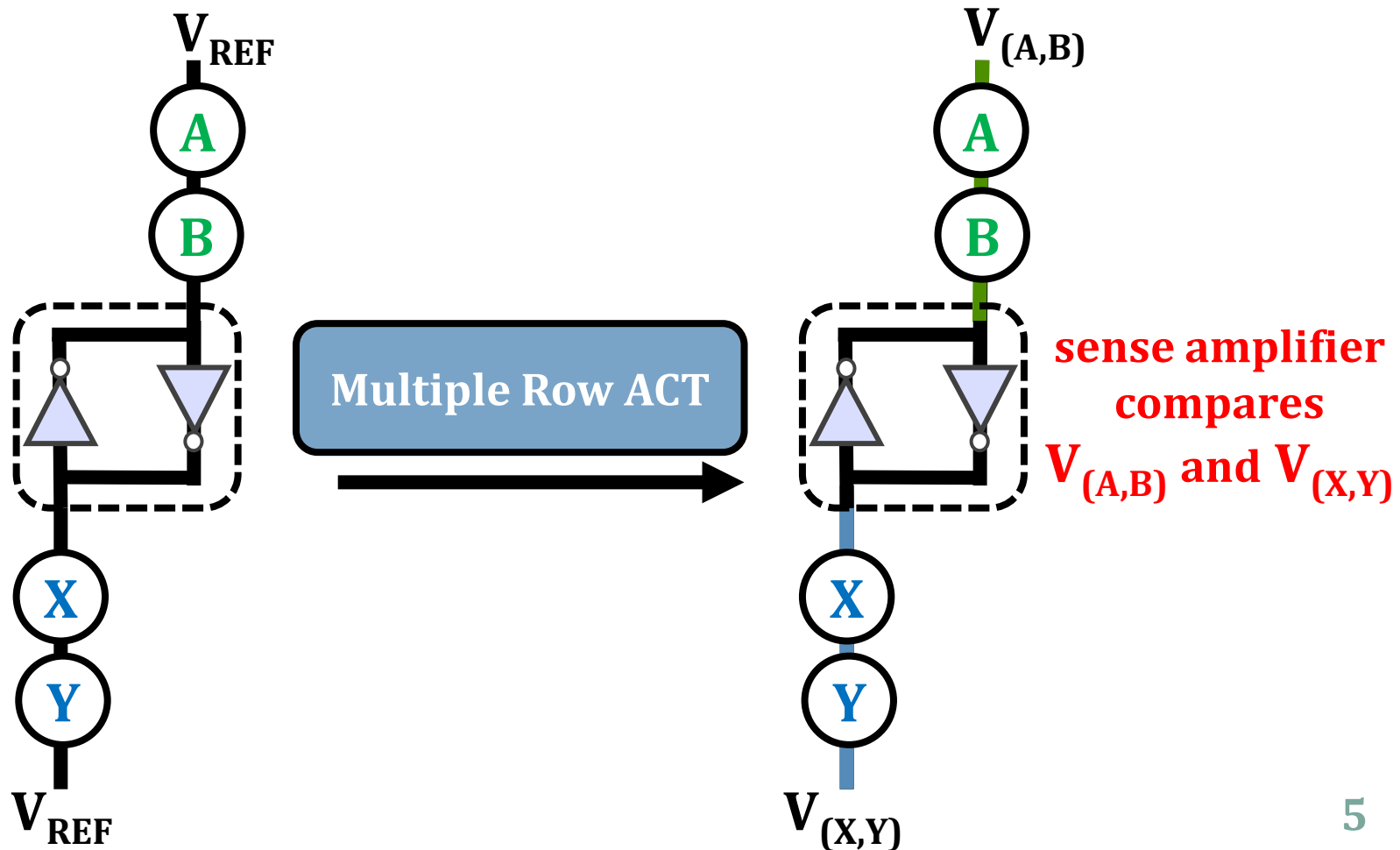
Key Idea: NOT Operation

Connect rows in neighboring subarrays through a **NOT gate** by consecutively activating rows

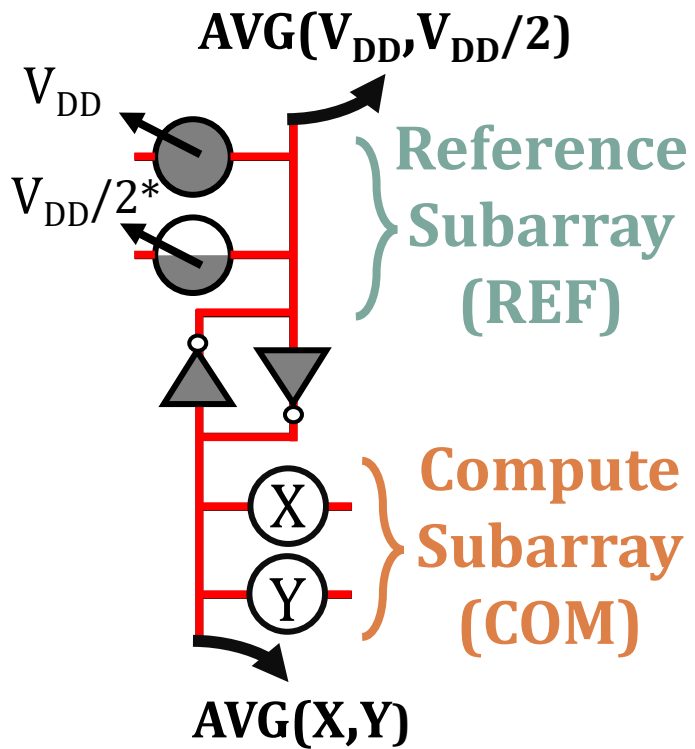


Key Idea: NAND, NOR, AND, OR

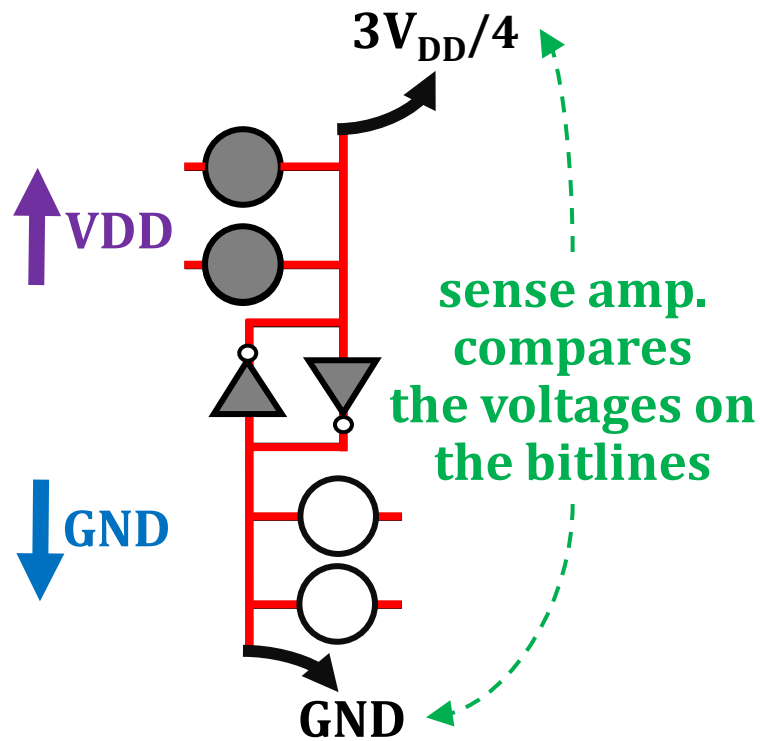
Manipulate the bitline voltage to express
a wide variety of functions using
simultaneous multi-row activation in neighboring subarrays



Two-Input AND and NAND Operations



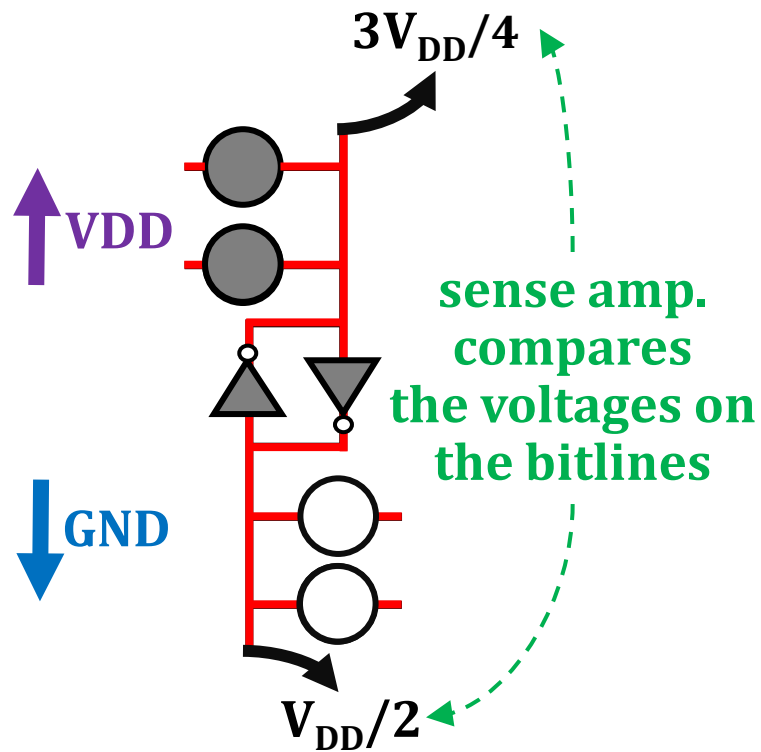
Two-Input AND and NAND Operations



$V_{DD}=1$ & $GND = 0$

X	Y	COM	REF
0	0	0	1

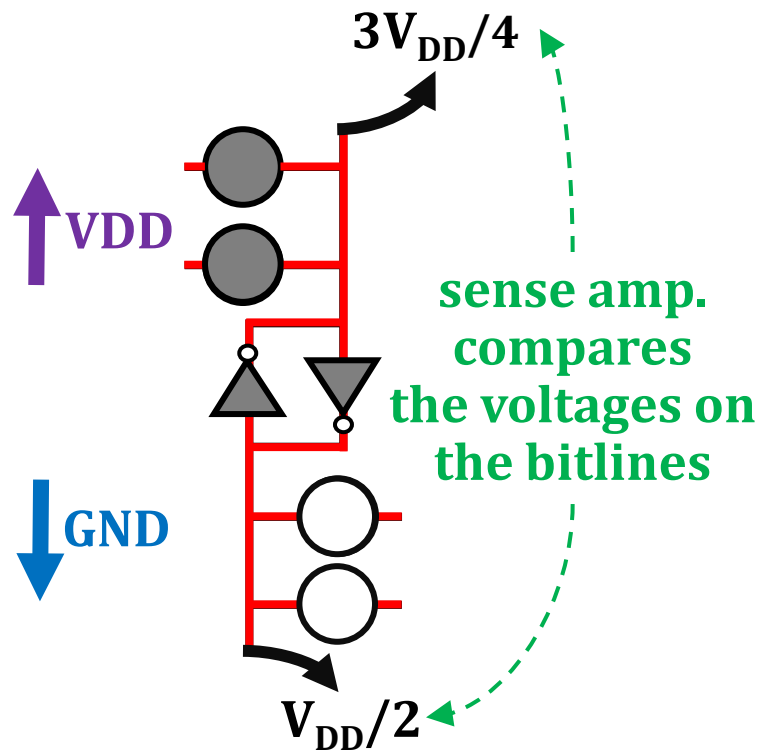
Two-Input AND and NAND Operations



$V_{DD}=1$ & $GND=0$

X	Y	COM	REF
0	0	0	1
0	1	0	1

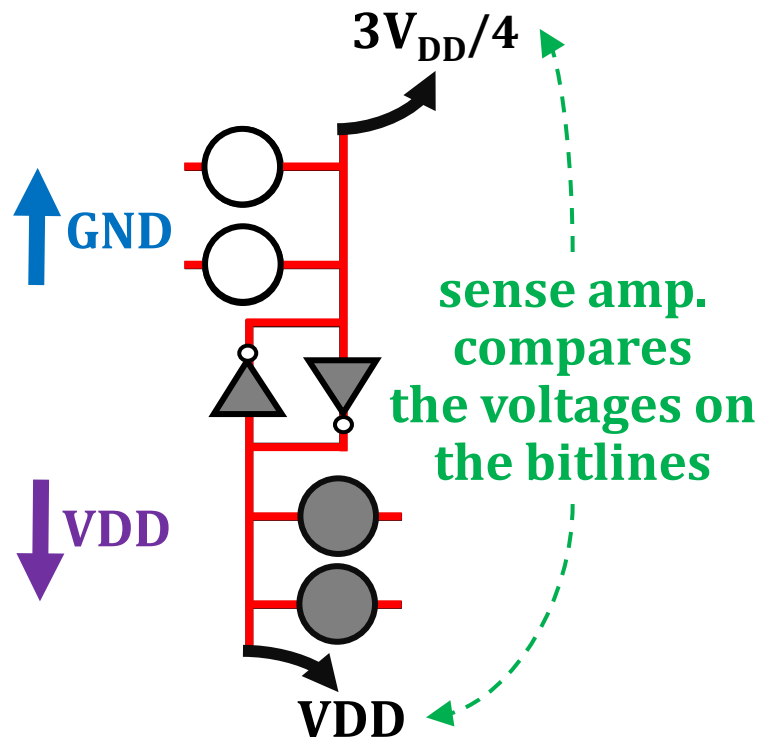
Two-Input AND and NAND Operations



$V_{DD}=1$ & $GND=0$

X	Y	COM	REF
0	0	0	1
0	1	0	1
1	0	0	1

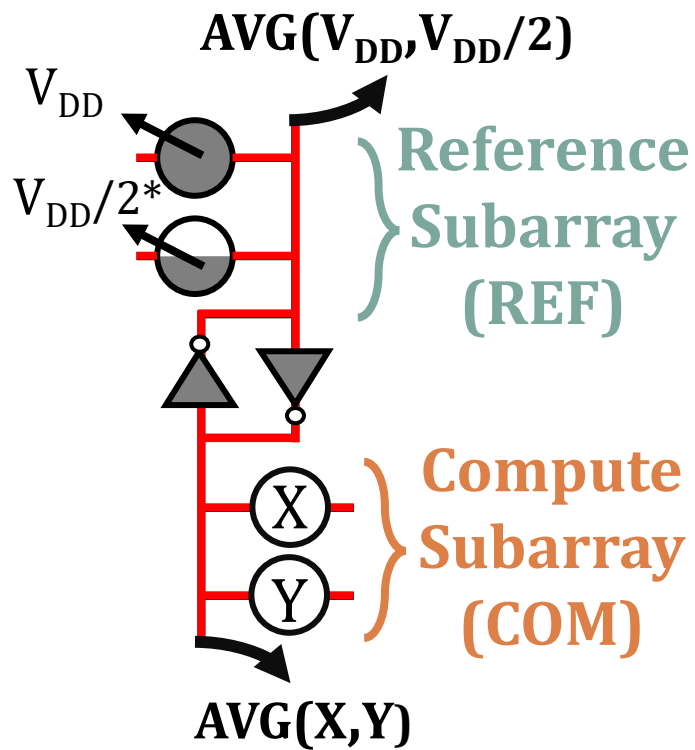
Two-Input AND and NAND Operations



$V_{DD}=1$ & $GND=0$

X	Y	COM	REF
0	0	0	1
0	1	0	1
1	0	0	1
1	1	1	0

Two-Input AND and NAND Operations



$V_{DD}=1$ & $GND = 0$

X	Y	COM	REF
0	0	0	1
0	1	0	1
1	0	0	1
1	1	1	0
		AND	NAND

Many-Input AND, NAND, OR, and NOR Operations

We can express AND, NAND, OR, and NOR operations by carefully manipulating the reference voltage

Functionally-Complete Boolean Logic in Real DRAM Chips: Experimental Characterization and Analysis

İsmail Emir Yüksel Yahya Can Tuğrul Ataberk Olgun F. Nisa Bostancı A. Giray Yağlıkçı
Geraldo F. Oliveira Haocong Luo Juan Gómez-Luna Mohammad Sadrosadati Onur Mutlu

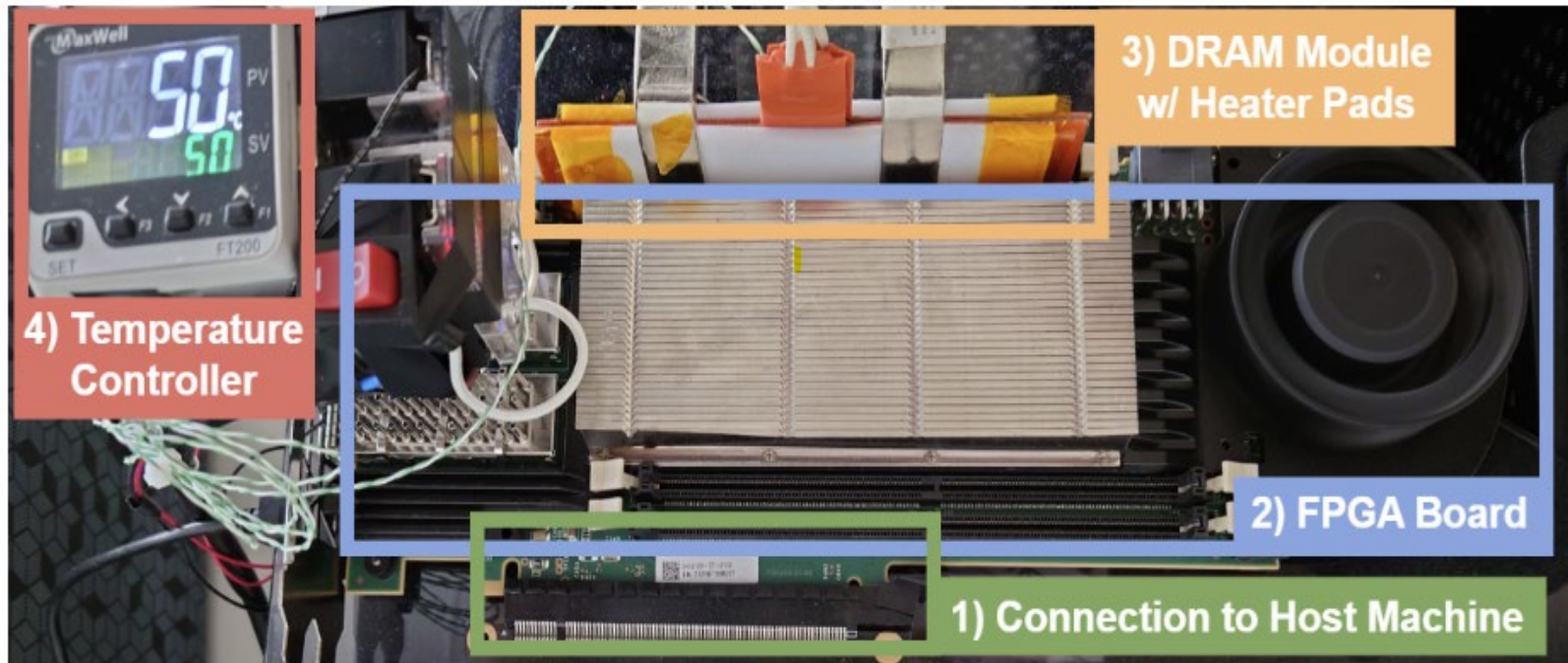
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(More details in the paper)

<https://arxiv.org/pdf/2402.18736.pdf>

DRAM Testing Infrastructure

- Developed from [DRAM Bender \[Olgun+, TCAD'23\]*](#)
- **Fine-grained control** over DRAM commands, timings, and temperature

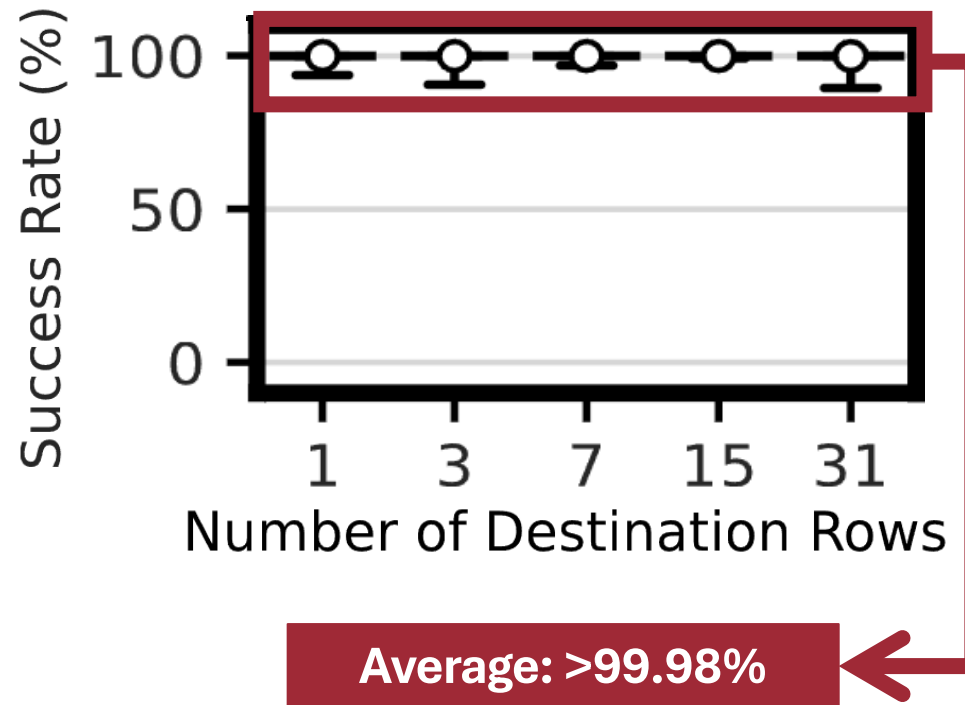


DRAM Chips Tested

- 256 DDR4 chips from two major DRAM manufacturers
- Covers different die revisions and chip densities

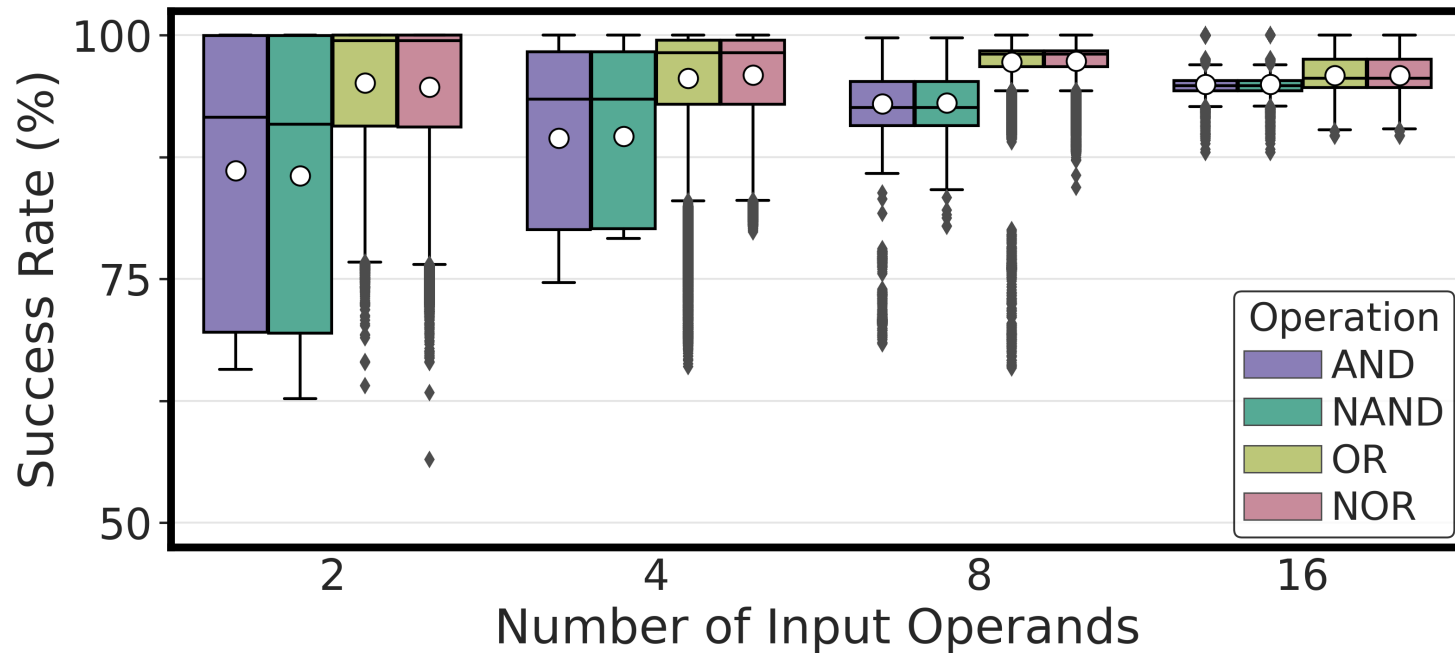
Chip Mfr.	#Modules (#Chips)	Die Rev.	Mfr. Date ^a	Chip Density	Chip Org.	Speed Rate
SK Hynix	9 (72)	M	N/A	4Gb	x8	2666MT/s
	5 (40)	A	N/A	4Gb	x8	2133MT/s
	1 (16)	A	N/A	8Gb	x8	2666MT/s
	1 (32)	A	18-14	4Gb	x4	2400MT/s
	1 (32)	A	16-49	8Gb	x4	2400MT/s
	1 (32)	M	16-22	8Gb	x4	2666MT/s
Samsung	1 (8)	F	21-02	4Gb	x8	2666MT/s
	2 (16)	D	21-10	8Gb	x8	2133MT/s
	1 (8)	A	22-12	8Gb	x8	3200MT/s

Robustness of Multi-RowCopy



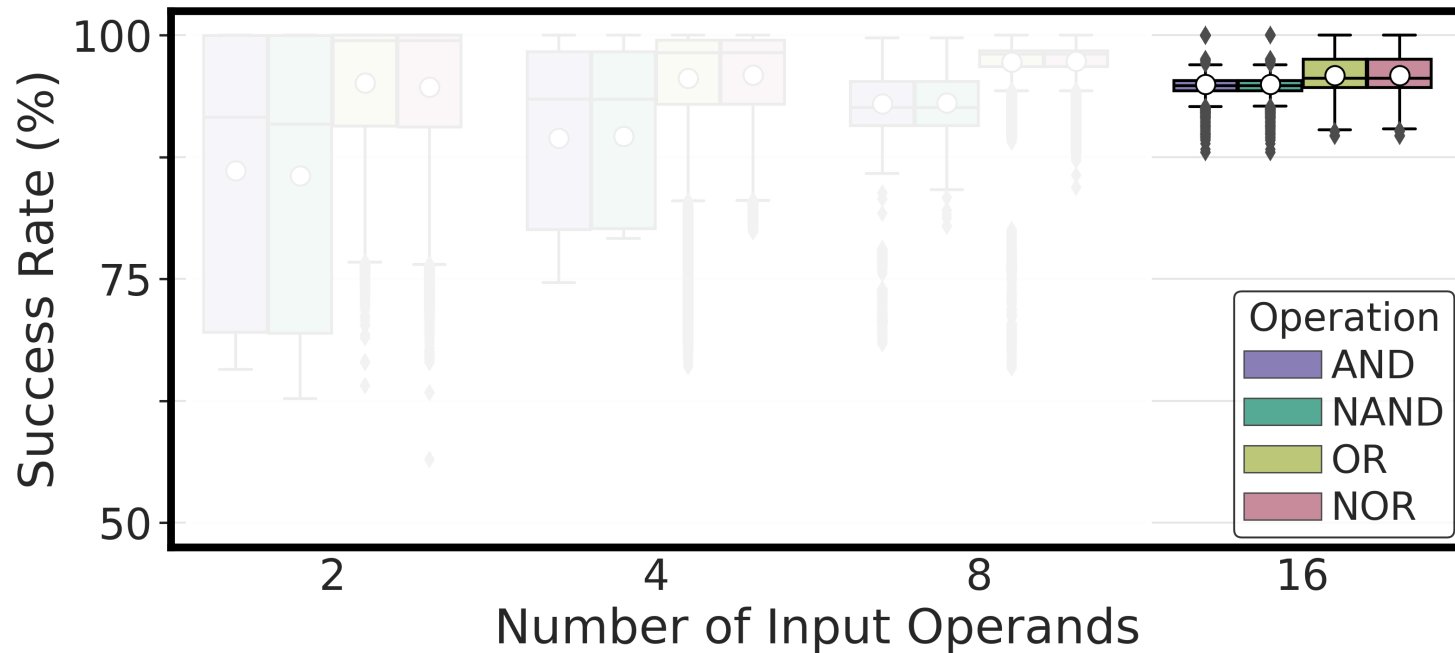
COTS DRAM chips can copy one row's content to up to 31 rows with a very high success rate

Performing AND, NAND, OR, and NOR



COTS DRAM chips can perform {2, 4, 8, 16}-input AND, NAND, OR, and NOR operations

Performing AND, NAND, OR, and NOR



**COTS DRAM chips can perform
16-input AND, NAND, OR, and NOR operations
with very high success rate (>94%)**

More on Functionally-Complete DRAM

- Ismail Emir Yüksel, Yahya Can Tuğrul, Ataberk Olgun, F. Nisa Bostancı, A. Giray Yağlıkçı, Geraldo F. Oliveira, Haocong Luo, Juan Gomez-Luna, Mohammad Sadrosadati, and Onur Mutlu,
"Functionally-Complete Boolean Logic in Real DRAM Chips: Experimental Characterization and Analysis"
Proceedings of the 30th International Symposium on High-Performance Computer Architecture (HPCA), April 2024.
[[Slides \(pptx\)](#)] [[pdf](#)]
[[arXiv version](#)]
[[FCDRAM Source Code](#)]

Functionally-Complete Boolean Logic in Real DRAM Chips: Experimental Characterization and Analysis

Ismail Emir Yüksel Yahya Can Tuğrul Ataberk Olgun F. Nisa Bostancı A. Giray Yağlıkçı
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More on Multi-Row Copy

- Ismail Emir Yuksel, Yahya Can Tugrul, F. Nisa Bostanci, Geraldo F. Oliveira, A. Giray Yaglikci, Ataberk Olgun, Melina Soysal, Haocong Luo, Juan Gomez-Luna, Mohammad Sadrosadati, and Onur Mutlu,

"Simultaneous Many-Row Activation in Off-the-Shelf DRAM Chips: Experimental Characterization and Analysis"

Proceedings of the 54th Annual IEEE/IFIP International Conference on Dependable Systems and Networks (DSN), Brisbane, Australia, June 2024.

[[Slides \(pptx\)](#) ([pdf](#))]

[[arXiv version](#)]

[[SiMRA-DRAM Source Code \(Officially Artifact Evaluated with All Badges\)](#)]

Officially artifact evaluated as both code and dataset available, reviewed and reproducible.



Simultaneous Many-Row Activation in Off-the-Shelf DRAM Chips: Experimental Characterization and Analysis

İsmail Emir Yüksel¹ Yahya Can Tuğrul^{1,2} F. Nisa Bostancı¹ Geraldo F. Oliveira¹
A. Giray Yağlıkçı¹ Ataberk Olgun¹ Melina Soysal¹ Haocong Luo¹
Juan Gómez-Luna¹ Mohammad Sadrosadati¹ Onur Mutlu¹

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²TOBB University of Economics and Technology

Acknowledgments



Think BIG, Aim HIGH!

<https://safari.ethz.ch>

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